Search Notes

Application/Control No.	Applicant(s)/Patent Under Reexamination
10586451	BARTSCH ET AL.
Examiner	Art Unit
SUN IAE VI OEWE	1626

SEARCHED				
Subclass	Date	Examiner		

SEARCH NOTES				
Search Notes	Date	Examiner		
restriction requirement	10-1-2008	sl		

INTERFERENCE SEARCH				
Subclass	Date	Examiner		
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U.S. Patent and Trademark Office Part of Paper No. : 20081001